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XPX2N2U8RD

# 20V N-Channel Enhancement Mode MOSFET



#### Description

The XPX2N2U8RD uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 2.5V. This device is suitable for use as a Battery protection or in other Switching application.

#### Application

solar road lights

Load switch

Uninterruptible power supply

EAS

 $\mathbf{P}_{\mathsf{D}}$ 

RθJA

R<sub>θ</sub>JC

TJ, TSTG

V DS =20V,ID =80A RDS(ON)=2.8mΩ (typ) @ VGS=4.5V RDS(ON)=4.0mΩ (typ) @ VGS=2.5V





110

81

65

4

-55 to +175

mJ

W

°C/W

°C/W

°C

### Package Marking and Ordering Information

Product ID	Pack	Marking	<b>Qty(PCS)</b> 5000	
XPX2N2U8RD	PDFN5*6-8L	XPX2N2U8RD XXX YYYY		
bsolute Maximur	m Ratings (T <sub>c</sub> =25℃unless otherwise n	oted)		
Symbol	Parameter	Max.	Units	
VDSS	Drain-Source Voltage	20	V	
VGSS	Gate-Source Voltage	±12	V	
I₀@Tc=25℃	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	80	А	
I₀@Tc=100℃	Continuous Drain Current, $V_{GS}$ @ $10V^1$	59	А	
IDM	Pulsed Drain Current note1	360	А	

Single Pulsed Avalanche Energy note2

Power Dissipation

Thermal Resistance, Junction to Case

Thermal Resistance Junction-Case 1

Operating and Storage Temperature Range



#### Electrical Characteristics (TJ=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions		Тур	Max	Units	
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =250µA	20	24		V	
∆BVDSS/∆TJ	BVDSS Temperature Coefficient	SS Temperature Coefficient Reference to $25^{\circ}$ C , I <sub>D</sub> =1mA		0.018		V/℃	
VGS(th)	Gate Threshold Voltage	$V_{DS}$ = $V_{GS}$ , $I_D$ =250 $\mu$ A		0.65	1.0	V	
RDS(ON)	Static Drain-Source On-Resistance	V <sub>GS</sub> =4.5V, I <sub>D</sub> =30A		2.8	4.0		
RDS(ON)	Static Drain-Source On-Resistance	V <sub>GS</sub> =2.5V, I <sub>D</sub> =20A		4.0	6.0	mΩ	
IDSS	Zero Gate Voltage Drain Current	V <sub>DS</sub> =20V,V <sub>GS</sub> =0V			1	μA	
IGSS	Gate-Body Leakage Current	V <sub>GS</sub> =±10V, V <sub>DS</sub> =0V			±100	nA	
Ciss	Input Capacitance			3200		pF	
Coss	Output Capacitance	V <sub>DS</sub> =10V,V <sub>GS</sub> =0V,f=1MHZ		460			
Crss	Reverse Transfer Capacitance			446			
Qg	Total Gate Charge			11.05		nC	
$Q_gs$	Gate-Source Charge	V <sub>GS</sub> =4.5V,V <sub>DS</sub> =10V,I <sub>D</sub> =30A		1.73			
$Q_gd$	Gate-Drain Charge			3.1			
tD(on)	Turn-on Delay Time			9.7			
tr	Turn-on Rise Time	V <sub>GS</sub> =4.5V, V <sub>DS</sub> =10V, I <sub>D</sub> =30A		37		ns	
tD(off)	Turn-off Delay Time	R <sub>GEN</sub> =1.8Ω		63			
t <sub>f</sub>	Turn-off fall Time			52			
V <sub>SD</sub>	Diode Forward Voltage	Is=7.6A,V <sub>GS</sub> =0V			1.2	V	

Note :

- 1、The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%
- $3\,{\scriptstyle \sim}\,$  The power dissipation is limited by  $150\,{\rm ^{\circ}C}\,$  junction temperature
- 4. The data is theoretically the same as I<sub>D</sub> and I<sub>DM</sub>, in real applications, should be limited by total power dissipation.
- $5\times$  EAS condition: TJ=25  $^\circ\!\!\mathrm{C}$  , VDD=15V, VG=4.5V, RG=25 $\Omega$  , L=0.5mH, IAS=21A









Figure 5: Gate Charge Characteristics



**Figure 4: Body Diode Characteristics** 



**Figure 6: Capacitance Characteristics** 











\_L1

# Package Mechanical Data-DFN5\*6-8L-JQ Single





		Com	mon		
Symbol	mm		Inch		
	Mim	Max	Min	Max	
A	1.03	1.17	0.0406	0.0461	
b	0.34	0.48	0.0134	0.0189	
С	0.824	0.0970	0.0324	0.082	
D	4.80	5.40	0.1890	0.2126	
D1	4.11	4.31	0.1618	0.1697	
D2	4.80	5.00	0.1890	0.1969	
E	5.95	6.15	0.2343	0.2421	
E1	5.65	5.85	0.2224	0.2303	
E2	1.60	/	0.0630	/	
e	1.27	BSC	0.05	BSC	
L	0.05	0.25	0.0020	0.0098	
L1	0.38	0.50	0.0150	0.0197	
L2	0.38	0.50	0.0150	0.0197	
Н	3.30	3.50	0.1299	0.1378	
Ι	/	0.18	/	0.0070	



#### Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time
Pb device	<b>245℃</b> ± <b>5</b> ℃	5sec±1sec
Pb-Free device	<b>260</b> °C <b>+0/-5</b> °C	5sec±1sec



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